



IMtc/04



21st IEEE Instrumentation and Measurement Technology Conference *Always On: Instrumentation and Measurement in the Networked World* Como, Italy, 18-20 May 2004 (Tuesday -Thursday)

Call for Papers

The conference studies all aspects of instrumentation, measurement and control technologies - theory, research and development and applications. Program topics include but not limited to:

MEASUREMENT SCIENCE

Metrology & standards
Measurement principles education

DATA ACQUISITION

Sensors & transducers, smart sensors
Calibration & self-calibration
A/D, D/A & data acquisition
Remote measurements & telemetry
Waveform measurement, analysis & generation
Sensitivity & noise

INSTRUMENTATION TECHNOLOGIES

Automated test & measurement systems
Instrumentation & prototype development
Frequency, microwave and laser I&M systems
Integrated & visual measurement systems
Human-computer interface
Networked & distributed measurements
Autonomous sensing & measurement systems
Non-invasive instrumentation & measurement
Measurement microsystems
Testing & diagnosis of I&M systems
Fault-tolerant & resilient I&M systems

DATA PROCESSING TECHNOLOGIES

Analog, digital & mixed-signal processing
Image processing & imaging systems
Identification, control & distributed monitoring
System prediction & sensor fusion
Soft computing for intelligent I&M systems

PHYSICAL QUANTITIES MEASUREMENTS

Electrical & power measurements
Dielectric, magnetic and EMC measurements
Temperature, moisture & humidity measurements
Mechanical quantities & material analysis
Optical & nuclear measurements
Chemical & biological measurements

MEASUREMENT APPLICATIONS

Robotics, industrial automation & manufacturing
Automotive & transportation
Avionics & aerospace
Environmental monitoring
Medicine & science
Security & biometrics
Telecommunications
Virtual environments

Authors should submit electronically 1 copy of an extended abstract (3 or 4 pages) *in English*, reflecting new or advanced study, theory or application and including the significance of the contribution, a list of references and figures or tables. Abstracts must be prepared according to the Abstract Preparation Guide and must be accompanied by an Abstract Submission Form. Both documents may be downloaded from the IMTC website – <http://www.ieee-imtc.org> Check the website for all instructions and details. Important dates:

- **10 October 2003** – Abstract submission deadline – submit to lee.myers@ieee.org
- **19 December 2003** – Author notification of acceptance or rejection
- **1 March 2004** – Deadline for receipt of final manuscript

Papers will be reviewed by the IMTC International Program Committee. Authors of accepted abstracts *must guarantee they will register at the conference, pay registration fees, attend and present their papers*. An accepted paper will be published in the proceedings only if the final manuscript is accompanied by registration form(s) and fee(s) for at least one of the authors (only *full member/non-member fees* will be allowed – *no exceptions!*) One author registration will cover publication of up to 2 accepted papers; each additional paper with the same registration will require a printing contribution of US\$50. Authors of presented papers are invited to submit extended manuscripts to the special issue of *IEEE Transactions on Instrumentation & Measurement* on IMTC/2004, to be published in 2005.

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